

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/608,914	AGRAWAL, AVNEESH
Examiner	Art Unit	
Emmanuel Bayard	2611	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
375	130	8/30/06	z-15
	132	8/30/06	C-1